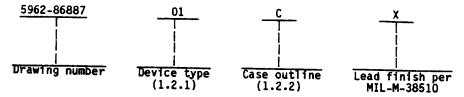
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- SCOPE
- $1.1~\underline{\text{Scope}}$. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".
 - 1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type

Generic number

Circuit function

01

OP-227A

Dual, low-offset, low noise operational amplifier

1.2.2 Case outline. The case outline shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter

Case outline

C

D-1 (14-lead, 1/4" x 3/4"), dual-in-line package.

1.3 Absolute maximum ratings. 1/

1.4 Recommended operating conditions.

Supply voltage (VCC) - - - - - - - - - ± 4.5 V dc to ± 18 V dc Ambient operating temperature range- - - - - - - - - ± 5.5 C to ± 12.5 C

1/ UnTess otherwise specified, all voltages are referenced to ground.

7/ The inputs are protected by back-to-back diodes. Current limiting resistors are not used in order to achieve low noise. If differential input voltage exceeds ±0.7 V, the input current should be limited to 25 mA.

3/ For T_A greater than 106°C, derate linearly at 11.3 mW/°C.

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
- 3.2.1 Terminal connections and logic diagram. The terminal connections and logic diagram shall be as specified on figure 1.
 - 3.2.2 Case outline. The case outline shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended ambient operating
- 3.4 <u>Marking</u>. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

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Test	Symbol		Conditions C < TA < +125°C	Group A	i	mits	Unit
		; ±	$VS = \pm 15 V$ otherwise specified)	subgroups	; Min - 	Max	T
Input offset voltage	VIO			1		i ! 80	<u>Ι</u> μ V
	!	1		2, 3	+	180	-)
Input offset current	110			1	+	35	nA
				2, 3	 	1 50	-¦
Input bias current	IIB	-		 1	┼	40	_[
				2, 3	1	60	-
Average input offset drift $\frac{1}{2}$	TC VIO	- 		1,2,3	 	1.0	μ٧/*(
Power supply rejection ratio	 PSRR	 V _S = ±4 to	±18 ∀	<u>i</u>	<u>i</u>	1 10	
		!		1 2, 3	 	16	-
Common mode rejection ratio	CMRR	V _{CM} = ±11 V		1 1	1 114	1	i I dB
	1	VCM = ±10 V		1 2, 3	108		
arge signal voltage gain	AVOL	1	R _L > 2 kilohms	1 4	1		
	1	1	WE Z E KITOIMIS	<u> </u>	1000		V/mV
	į	 Va		5, 6	600		i
· · · · · · · · · · · · · · · · · · ·		 0 = *10 V;	R _L ≥ 600 ohms	1 4	800]
input voltage range	IVR	T _A = 25°C		1	±11.0		i V
		T _A = -55°C,	+125°C 1/	2, 3	±10.0		i !
utput voltage swing	VOP	RL > 2 kilor	nms	4	±12		
	i			5, 6	±11.5		
		RL > 600 ohn	is	4	±10		
lew rate	SR		R _L > 2 kilohms		1.7		V/µS
nput noise voltage density	IE _n	T _A = 25°C	f ₀ = 10 Hz			6.0	<u>_nv</u> _
			$f_0 = 1,000 \text{ Hz}$	i i		3.9	√ Hz

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TABLE I	• Electri	cal performance	characteristics -	Continued.			
Test	 Symbol 	-55°C < -	itions <u>1/</u> TA < +125°C +15 V wise specified)	 Group A subgroups	ĺ	mits Max	Unit
Input noise current density	In	f ₀ = 10 Hz, T _A	= 25°C	7		5.66	√ Hz
Gain-bandwith product <u>1</u> /	GBW	f ₀ = 1,000 Hz, 		4	5.0	0.99 	 MHz
Power consumption	P _D	 Each amplifier,	T _A = 25°C	1		140	i mW
Input offset voltage match	v _{os}	T _A = 25°C	= 25°C			80	ĮμV
		T _A = -55°C, +12	5°C	2, 3		180	1 . [
Average noninverting bias current		 IB+ = IB+A + IB+B	T _A = 25°C	1		±40	nA
	i 	2 	TA = -55°C,	2,3		±60	i
Noninverting offset current	I _{OS} +	IOS+ = I _{B+A} - I _{B+B}	TA = 25°C	1		±60	j
			TA = -55°C, TA = 125°C	2, 3	 	±90	
Inverting offset current	I _{0S} -	IOS- = IB-A - I _{B-B}	TA = 25°C	1		±60	
	İ		TA = -55°C, TA = 125°C	2, 3] 	±90	

1/ Guaranteed if not tested.

- 3.6 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

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^{3.5 &}lt;u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

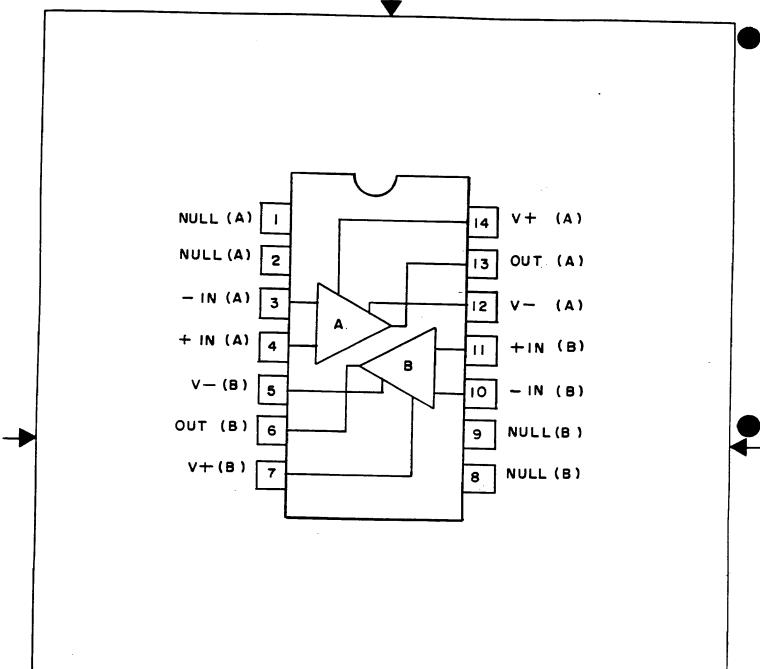


FIGURE 1. Terminal connections and logic diagram. (top view)

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- 3.8 <u>Verification and review.</u> DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section $\frac{4}{1}$ of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening.</u> Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - Tests shall be as specified in table II herein.
 - b. Subgroups 8, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*, 2, 3, 4
Group A test requirements (method 5005)	1, 2, 3, 4, 5, 6, 7
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3
Additional electrical subgroups for group C periodic inspections	

^{*}PDA applies to subgroup 1.

- PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
- NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
 - 6.2 Replaceability. Replaceability is determined as follows:
 - a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
 - b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/13504BCX.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number 1/	Replacement military specification part number
5962-8688701CX	64155 54186 06665	OP-227AJ/883B MP OP-227AY OP-227A883	M38510/13504BCX

 $\frac{1}{\text{Caution}}$. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name
64155	Linear Technology, Inc. 1630 McCarthy Blvd. Milpitas, CA. 95035-7487
54186	Micro Power Systems, Inc. 3100 Alfred Street Santa Clara, CA. 95050-3674
06665	Precision Monolithic, Inc. 1500 Space Park Drive P. O. Box 58020 Santa Clara, CA. 95050

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